L Number	Hits	Search Text	DB	Time stamp
-	56177	(test$3) near (DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:54
-	23982	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:56
-	9894	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).ab. ((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).ti. ((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	918	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:57
-	93	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/725.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	149	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/731.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	464	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:58
-	240	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/734.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	354	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/736.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	454	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 16:59
-	66	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/741.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00
-	123	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00

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-	6272	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits))).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00
-	1093	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and ("operating system")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:00
-	20	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation configuration))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:01
-	12	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation))) and 714/744.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:01
-	1040	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:02
-	2120	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation configuration)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:02
-	445	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation) and (device driver)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:02
-	53	((test$3 evaluat$3) near ((DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits) and (software simulation) and (driver)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:04
-	1588	(test$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:06
-	14	(test$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:07
-	8	(test$3 near (("semiconductor device" DUT CUT SUT circuit circuits "device under test" "circuit under test" "system under test") and (data pattern patterns signal signals information input bit bits)) and (software simulation) and driver).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:09
-	2	6578166.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:14

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-		2	6678643.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:14
-		2	6591205.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:12
-		2	5557559.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:12
-		2	5497378.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:12
-		0	(6678643.pn. and 6678643.pn. and 6591205.pn. and 5557559.pn. and 5497378.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:19
-		2	(6678643.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:18
-		2	(5557559.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:18
-		2	5497378.pn. and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:18
-		2	(6591205.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:18
-		2	(6678643.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:18
-		8	(6678643.pn. or 6678643.pn. or 6591205.pn. or 5557559.pn. or 5497378.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:24
-		8	(6678643.pn. or 6678643.pn. or 6591205.pn. or 5557559.pn. or 5497378.pn.) and (test$3 simulation evaluat$3 DUT CUT SUT circuit$2 "device under test" "circuit under test" "system under test" data pattern patterns signal signals information input bit bits driver)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/16 17:24